

(19) World Intellectual Property
Organization
International Bureau



(43) International Publication Date
29 April 2004 (29.04.2004)

PCT

(10) International Publication Number
WO 2004/036945 A1

(51) International Patent Classification⁷: H04Q 7/38,
7/34, H04B 17/00

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(21) International Application Number:
PCT/EP2003/010873

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(22) International Filing Date: 1 October 2003 (01.10.2003)

(81) Designated States (national): JP, US.

(25) Filing Language: English

(84) Designated States (regional): European patent (AT, BE,
BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU,
IE, IT, LU, MC, NL, PT, RO, SE, SI, SK, TR).

(26) Publication Language: English

(30) Priority Data:
02023410.0 18 October 2002 (18.10.2002) EP

Published:

— with international search report
— before the expiration of the time limit for amending the
claims and to be republished in the event of receipt of
amendments

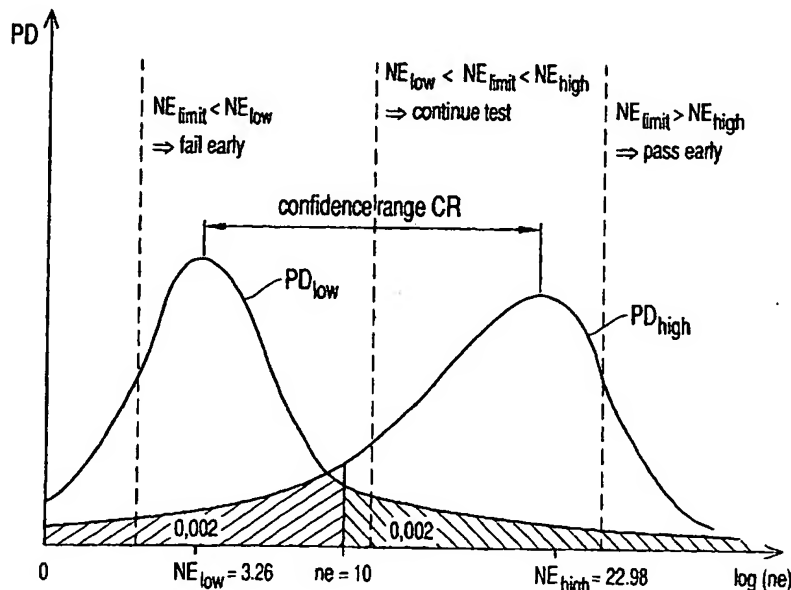
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For two-letter codes and other abbreviations, refer to the "Guid-
ance Notes on Codes and Abbreviations" appearing at the begin-
ning of each regular issue of the PCT Gazette.

(54) Title: METHOD TO EVALUATE WHETHER A TIME DELAY IS BETTER THAN A TIME LIMIT



(57) Abstract: A method for testing the time delay error ratio ER of a device against a maximal allowable time delay error ratio ER_{limit} with an early pass and/or early fail criterion, whereby the early pass and/or early fail criterion is allowed to be wrong only by a small probability D. ns time delays TD of the device are measured, thereby ne bad time delays of these ns time delays TD are detected. PD_{high} and/or PD_{low} are obtained, whereby PD_{high} is the worst possible likelihood distribution and PD_{low} is the best possible likelihood distribution containing the measured ne bad time delays with the probability D. The average numbers of erroneous bits NE_{high} and NE_{low} for PD_{high} and PD_{low} are obtained. NE_{high} and NE_{low} are compared with $NE_{limit} = ER_{limit}$ ns. If NE_{limit} is higher than NE_{high} or NE_{limit} is lower than NE_{low} the test is stopped.